

Search Notes

Application/Control No.

10/632,744

Examiner

Chi Q. Nguyen

Applicant(s)/Patent under
Reexamination

SANDOW, KIYOSHI

Art Unit

3635

SEARCHED

Class	Subclass	Date	Examiner
52	200	6/14/2005	CN
	309.5		
	309.3		
	202		
	201		
	107		
	45		
	204.5		
	506.01		
	788.1		
	802.1		
	28		
	38		
	39		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
52	200	6/14/2005	cn
	201		
	537		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
search related art with backward and forward search	6/14/2005	CN

Search Notes (continued)

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SEARCHED

Class	Subclass	Date	Examiner
52	39	6/14/2005	CN
	171.1		
	536		
	537		
	203		
	dig16		
	dig17		
40	578		
	561		
362	147		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR